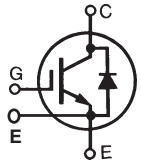
XPT™ 650V GenX4™ w/ Sonic Diode

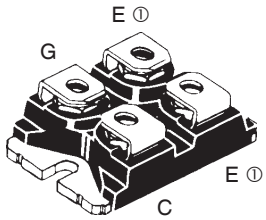
IXXN110N65B4H1

V_{CES} = 650V
I_{C110} = 110A
$V_{CE(sat)}$ ≤ 2.10V
$t_{fi(typ)}$ = 43ns

Extreme Light Punch Through
IGBT for 10-30kHz Switching



SOT-227B, miniBLOC
E153432



G = Gate, C = Collector, E = Emitter
① either emitter terminal can be used as Main or Kelvin Emitter

Symbol	Test Conditions	Maximum Ratings	
V_{CES}	T_J = 25°C to 175°C	650	V
V_{CGR}	T_J = 25°C to 175°C, R_{GE} = 1MΩ	650	V
V_{GES}	Continuous	±20	V
V_{GEM}	Transient	±30	V
I_{C25}	T_C = 25°C (Chip Capability)	230	A
I_{C25}	Terminal Current Limit	200	A
I_{C110}	T_C = 110°C	110	A
I_{F110}	T_C = 110°C	70	A
I_{CM}	T_C = 25°C, 1ms	650	A
SSOA (RBSOA)	V_{GE} = 15V, T_{VJ} = 150°C, R_G = 2Ω Clamped Inductive Load	I_{CM} = 220 @ $V_{CE} \leq V_{CES}$	A
t_{sc} (SCSOA)	V_{GE} = 15V, V_{CE} = 360V, T_J = 150°C R_G = 82Ω, Non Repetitive	10	µs
P_C	T_C = 25°C	750	W
T_J		-55 ... +175	°C
T_{JM}		175	°C
T_{stg}		-55 ... +175	°C
V_{ISOL}	50/60Hz t = 1min $I_{ISOL} \leq$ 1mA t = 1s	2500 3000	V~ V~
M_d	Mounting Torque Terminal Connection Torque	1.5/13 1.3/11.5	Nm/lb.in. Nm/lb.in.
Weight		30	g

Symbol	Test Conditions (T_J = 25°C, Unless Otherwise Specified)	Characteristic Values Min.	Typ.	Max.	
BV_{CES}	I_C = 250µA, V_{GE} = 0V	650			V
$V_{GE(th)}$	I_C = 250µA, V_{CE} = V_{GE}	4.0		6.5	V
I_{CES}	V_{CE} = V_{CES}, V_{GE} = 0V			50	µA
	T_J = 150°C			3	mA
I_{GES}	V_{CE} = 0V, V_{GE} = ±20V			±100	nA
$V_{CE(sat)}$	I_C = 110A, V_{GE} = 15V, Note 1		1.72	2.10	V
	T_J = 150°C		2.05		V

Features

- International Standard Package
- miniBLOC, with Aluminium Nitride Isolation
- 2500V~ Isolation Voltage
- Anti-Parallel Sonic Diode
- Optimized for 10-30kHz Switching
- Square RBSOA
- Short Circuit Capability
- High Current Handling Capability

Advantages

- High Power Density
- Low Gate Drive Requirement

Applications

- Power Inverters
- UPS
- Motor Drives
- SMPS
- PFC Circuits
- Battery Chargers
- Welding Machines
- Lamp Ballasts

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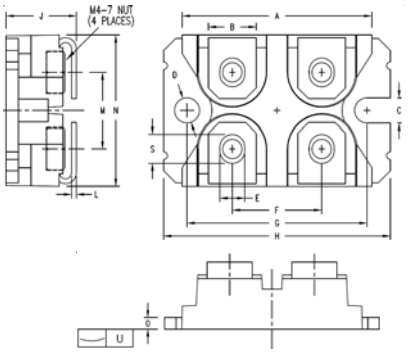
Symbol	Test Conditions (T_J = 25°C Unless Otherwise Specified)	Characteristic Values Min.	Typ.	Max.	
g_{fs}	I_C = 60A, V_{CE} = 10V, Note 1	30	52		S
C_{ies}	V_{CE} = 25V, V_{GE} = 0V, f = 1MHz		3650		pF
C_{oes}			470		pF
C_{res}			80		pF
Q_g	I_C = 110A, V_{GE} = 15V, V_{CE} = 0.5 • V_{CES}		183		nC
Q_{ge}			32		nC
Q_{gc}			83		nC
$t_{d(on)}$	**Inductive load, T_J = 25°C**		26		ns
t_{ri}	I_C = 55A, V_{GE} = 15V		40		ns
E_{on}	V_{CE} = 400V, R_G = 2Ω		2.20		mJ
$t_{d(off)}$	Note 2		146		ns
t_{fi}			43		ns
E_{off}			1.05	1.70	mJ
$t_{d(on)}$	**Inductive load, T_J = 150°C**		25		ns
t_{ri}	I_C = 55A, V_{GE} = 15V		40		ns
E_{on}	V_{CE} = 400V, R_G = 2Ω		3.00		mJ
$t_{d(off)}$	Note 2		140		ns
t_{fi}			110		ns
E_{off}			2.16		mJ
R_{thJC}				0.20	°C/W
R_{thCS}			0.05		°C/W

SOT-227B miniBLOC (IXXN)



SYM	INCHES MIN	INCHES MAX	MILLIMETERS MIN	MILLIMETERS MAX
A	1.224	1.260	31.10	32.00
B	.303	.327	7.70	8.30
C	.161	.173	4.10	4.40
D	.161	.173	4.10	4.40
E	.161	.173	4.10	4.40
F	.587	.598	14.90	15.20
G	1.181	1.201	30.00	30.50
H	1.488	1.508	37.80	38.30
J	.461	.484	11.70	12.30
L	.030	.033	0.75	0.85
M	.492	.512	12.50	13.00
N	.984	1.004	25.00	25.50
O	.075	.087	1.90	2.20
S	.181	.193	4.60	4.90
U	.000	.005	0.00	0.13

Reverse Sonic Diode (FRD)

Symbol	Test Conditions (T_J = 25°C Unless Otherwise Specified)	Characteristic Values Min.	Typ.	Max.	
V_F	I_F = 100A, V_{GE} = 0V, Note 1		1.7	2.3	V
	T_J = 150°C		1.8		V
I_{RM}	I_F = 100A, V_{GE} = 0V, T_J = 150°C		95		A
t_{rr}	$-di_F/dt$ = 1500A/μs, V_R = 300V		100		ns
R_{thJC}				0.42	°C/W

Notes:

1. Pulse test, t ≤ 300μs, duty cycle, d ≤ 2%.
2. Switching times & energy losses may increase for higher V_{CE}(clamp), T_J or R_G.

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IXYS MOSFETs and IGBTs are covered by one or more of the following U.S. patents: 4,835,592 4,860,072 4,881,106 4,931,844 5,017,508 5,034,796 5,049,961 5,063,307 5,187,117 5,237,481 5,381,025 5,486,715 6,162,665 6,259,123 B1 6,306,728 B1 6,404,065 B1 6,534,343 6,583,505 6,683,344 6,710,405 B2 6,710,463 6,727,585 6,759,692 6,771,478 B2 7,005,734 B2 7,063,975 B2 7,071,537 7,157,338B2

Fig. 1. Output Characteristics @ T_J = 25°C

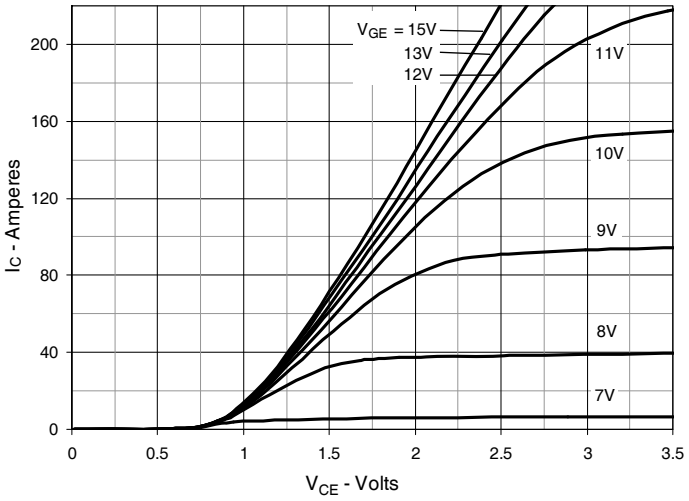

Fig. 2. Extended Output Characteristics @ T_J = 25°C

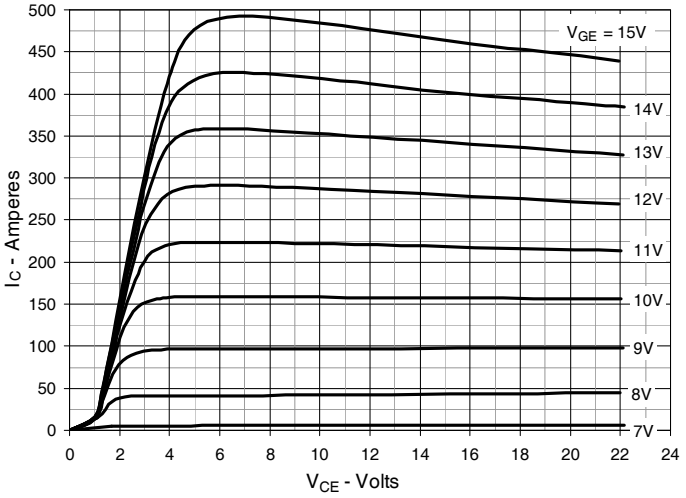

Fig. 3. Output Characteristics @ T_J = 150°C

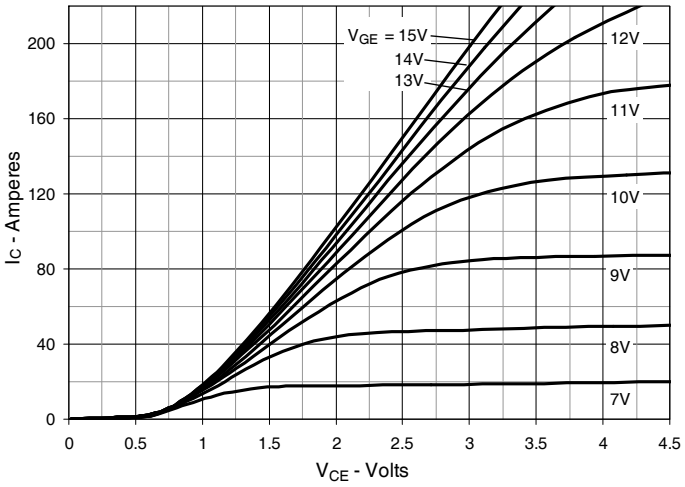

Fig. 4. Dependence of $V_{CE(sat)}$ on Junction Temperature

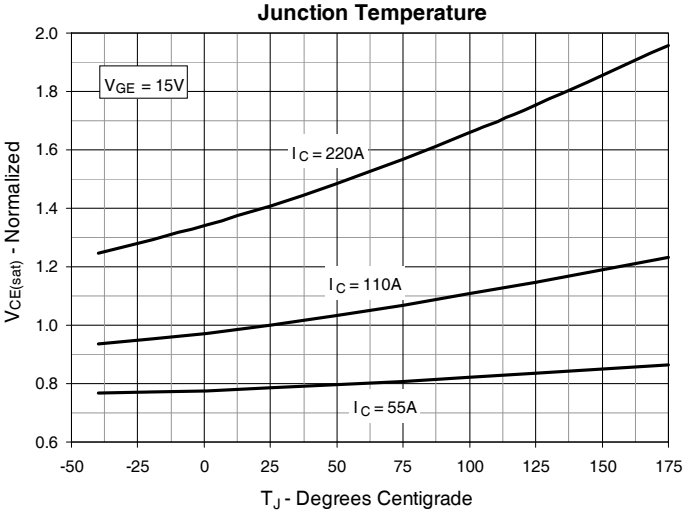

Fig. 5. Collector-to-Emitter Voltage vs. Gate-to-Emitter Voltage

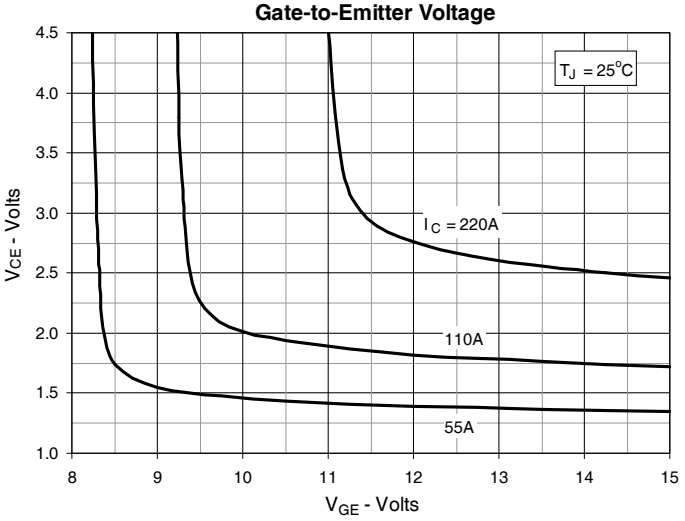

Fig. 6. Input Admittance

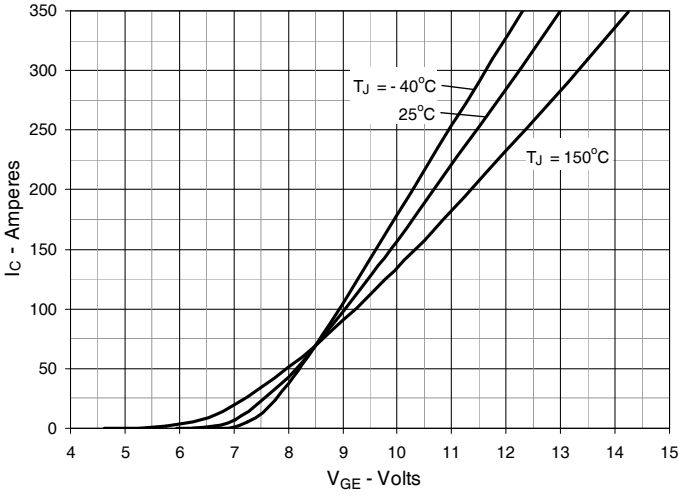

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Fig. 7. Transconductance

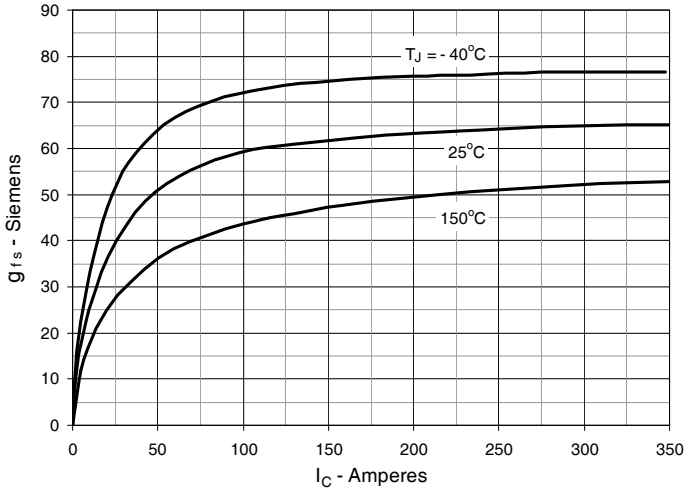

Fig. 8. Gate Charge

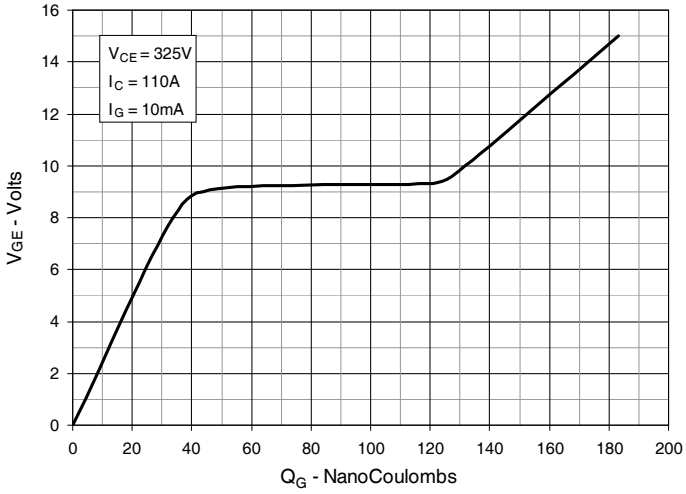

Fig. 9. Capacitance

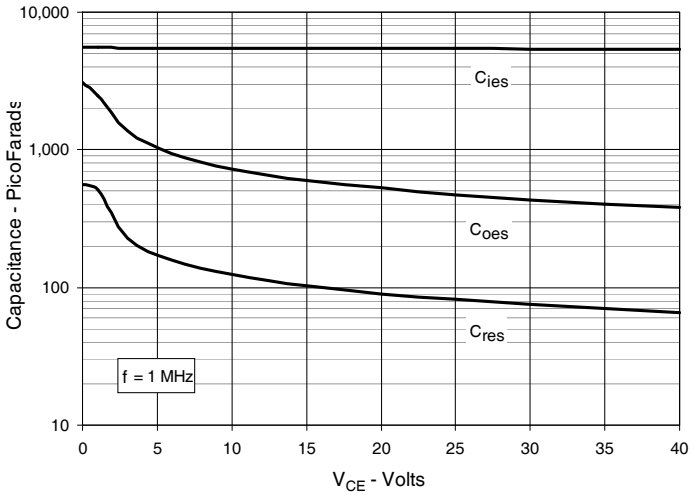

Fig. 10. Reverse-Bias Safe Operating Area

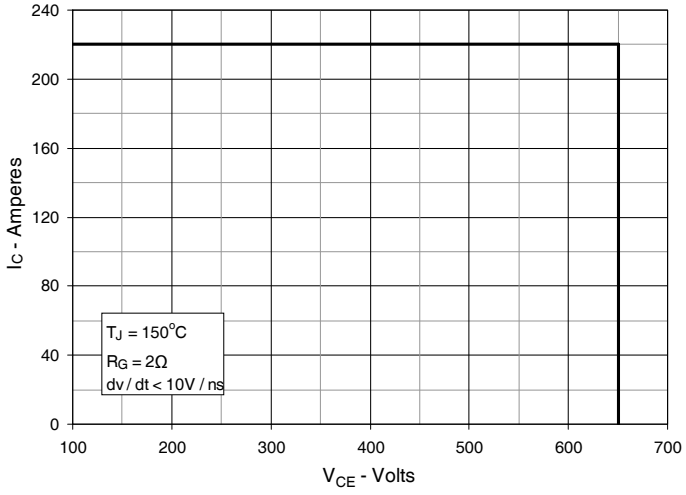

Fig. 11. Maximum Transient Thermal Impedance (IGBT)

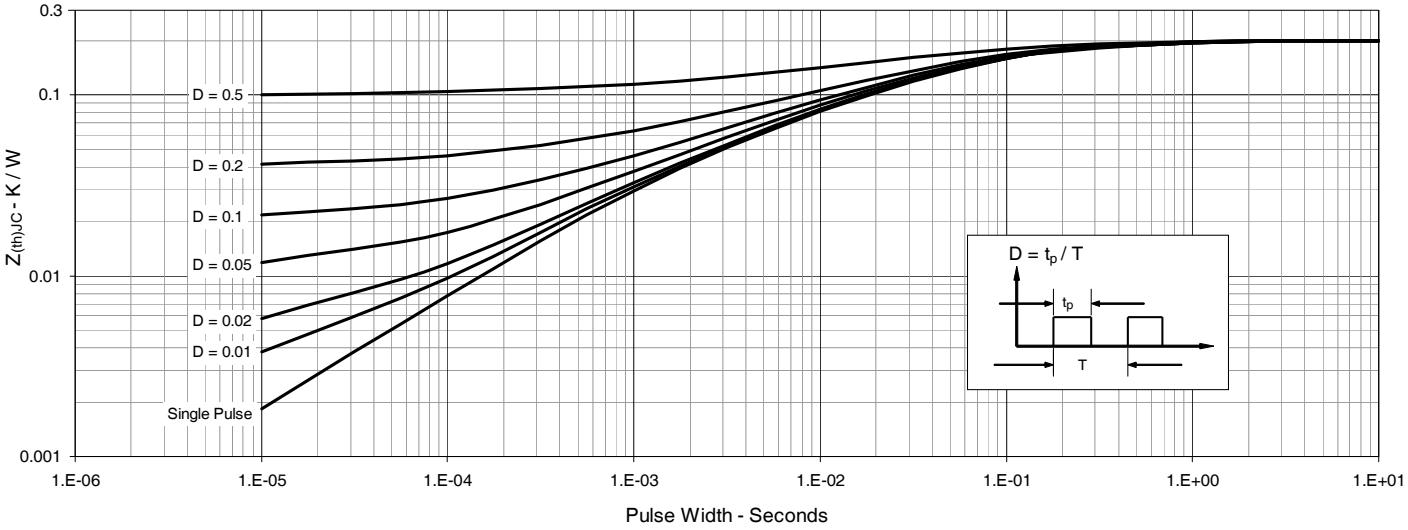

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Fig. 12. Inductive Switching Energy Loss vs. Gate Resistance

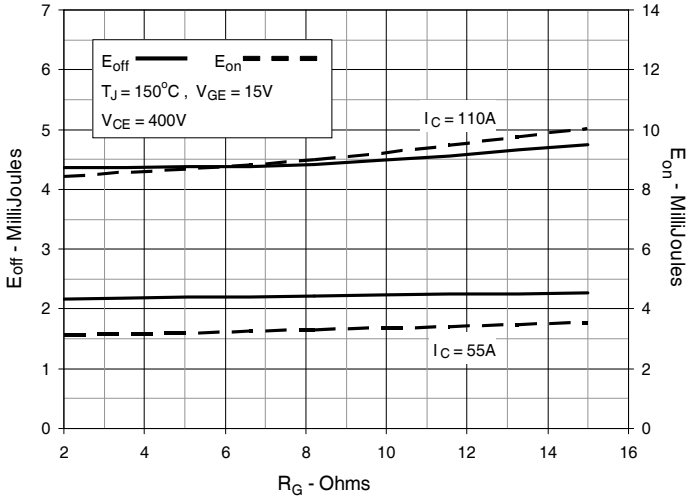

Fig. 13. Inductive Switching Energy Loss vs. Collector Current

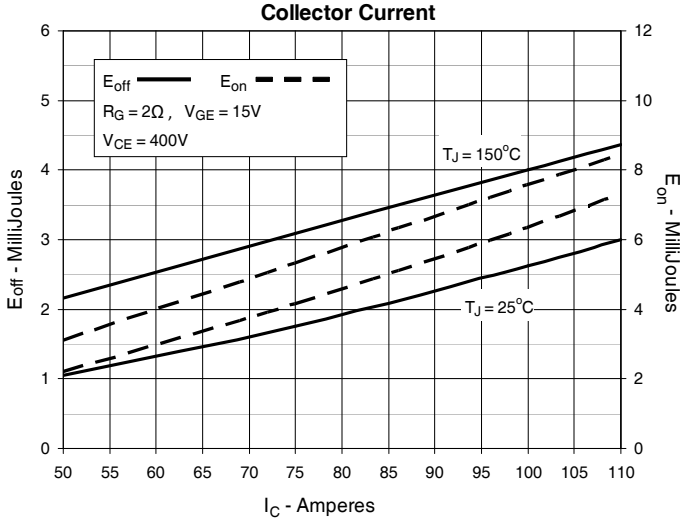

Fig. 14. Inductive Switching Energy Loss vs. Junction Temperature

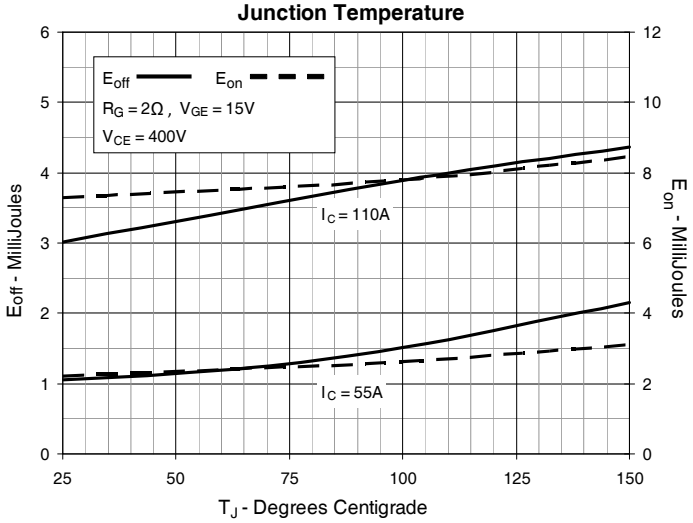

Fig. 15. Inductive Turn-off Switching Times vs. Gate Resistance

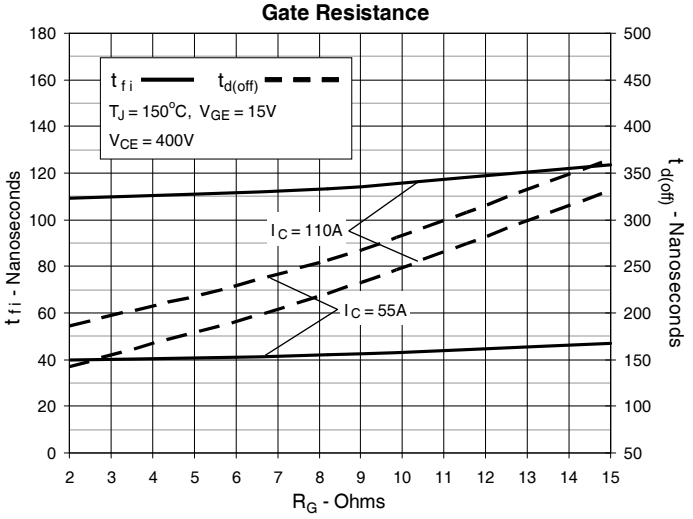

Fig. 16. Inductive Turn-off Switching Times vs. Collector Current

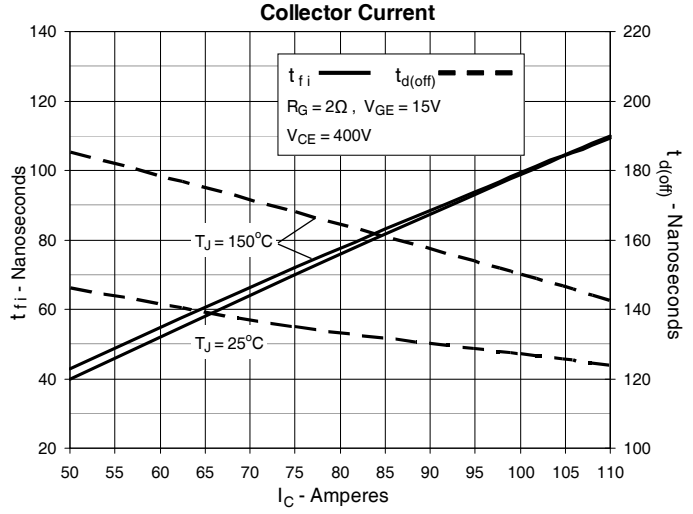

Fig. 17. Inductive Turn-off Switching Times vs. Junction Temperature

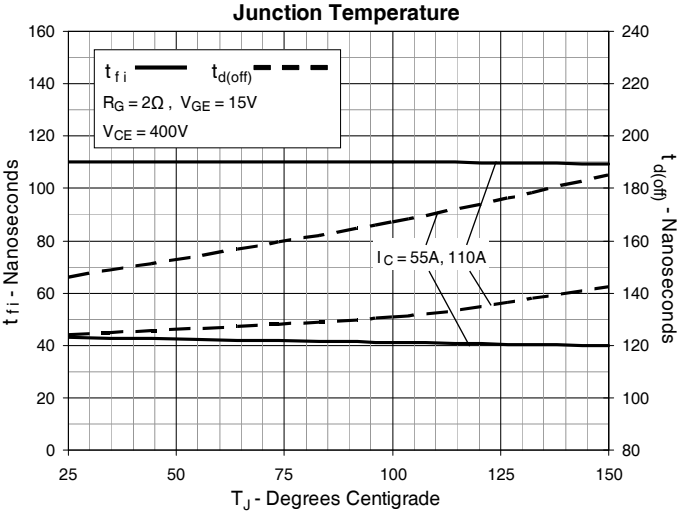

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Fig. 18. Inductive Turn-on Switching Times vs. Gate Resistance

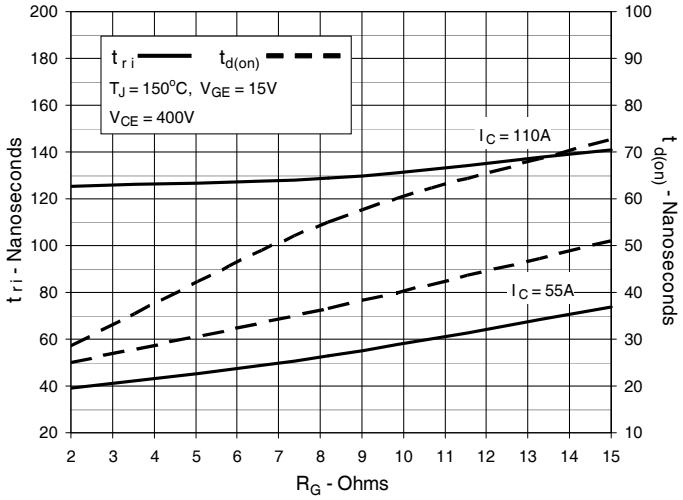


Fig. 19. Inductive Turn-on Switching Times vs. Collector Current

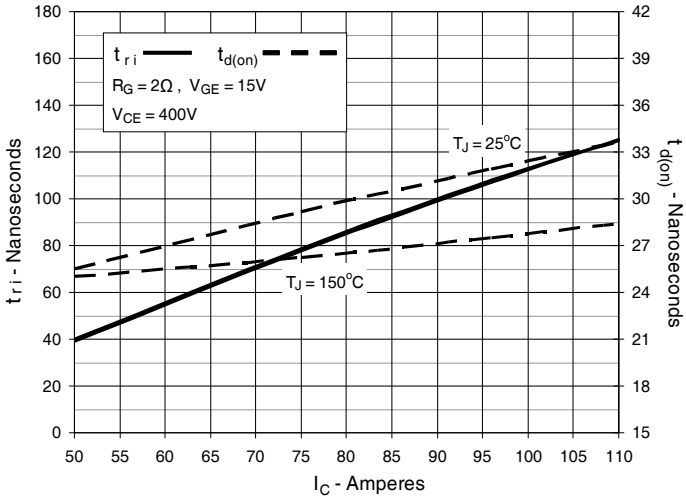


Fig. 20. Inductive Turn-on Switching Times vs. Junction Temperature

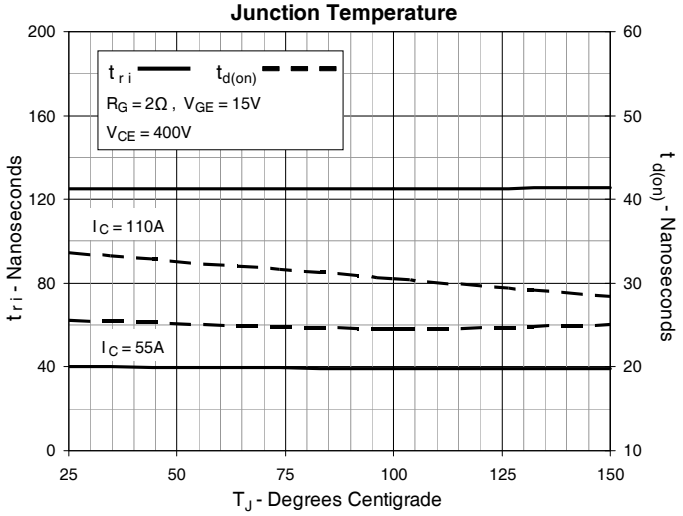


Fig. 21. Typ. Forward characteristics

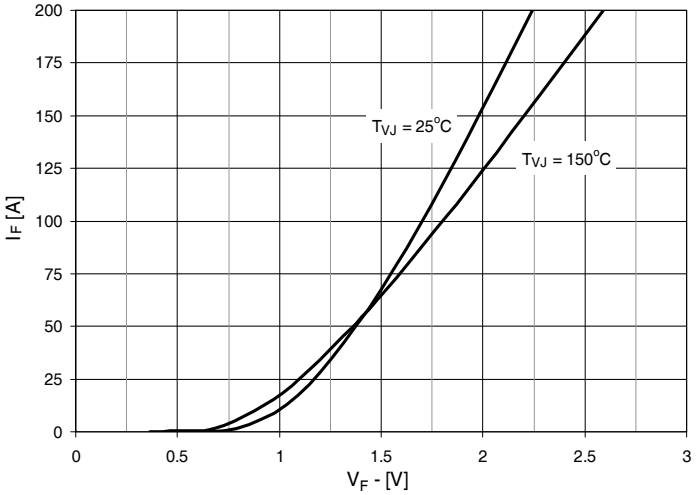


Fig. 22. Typ. Reverse Recovery Charge Q_{rr} vs. $-di_F/dt$

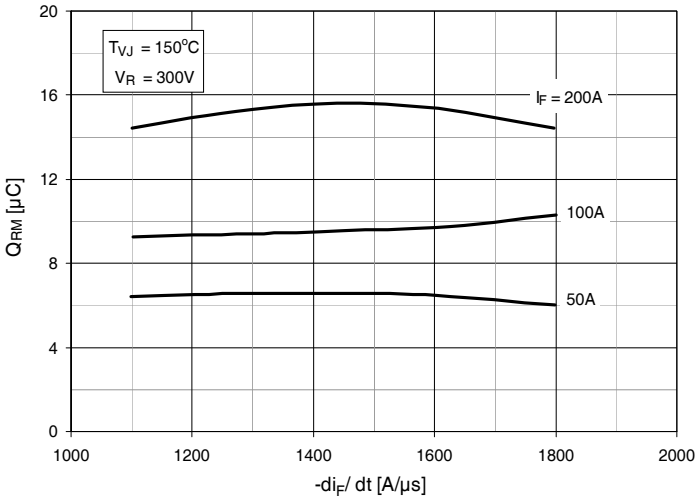


Fig. 23. Typ. Peak Reverse Current I_{RM} vs. $-di_F/dt$

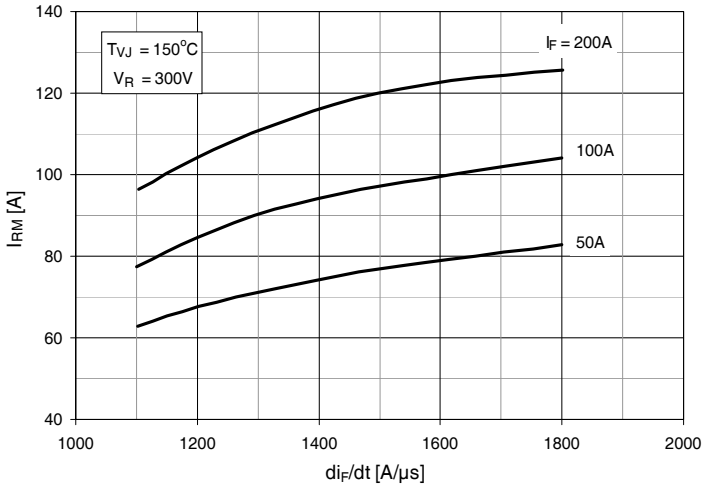


Fig. 24. Typ. Recovery Time t_{rr} vs. $-di_F/dt$

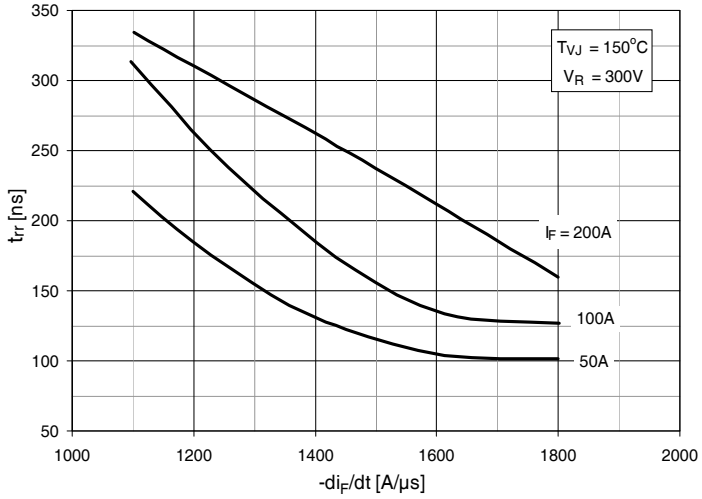


Fig. 25. Typ. Recovery Energy E_{rec} vs. $-di_F/dt$

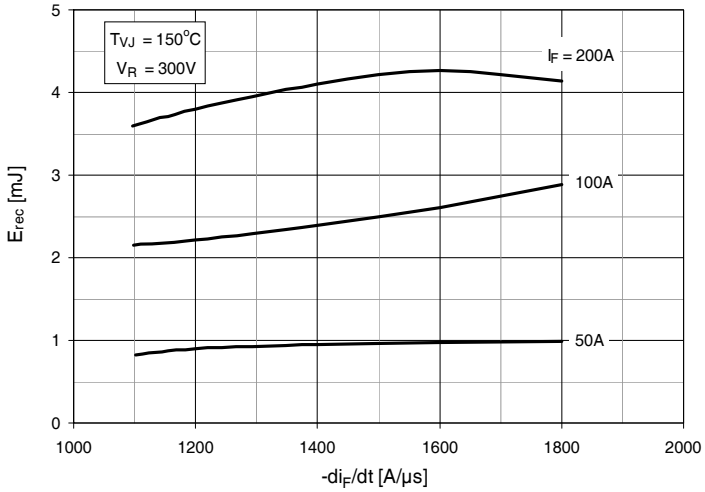
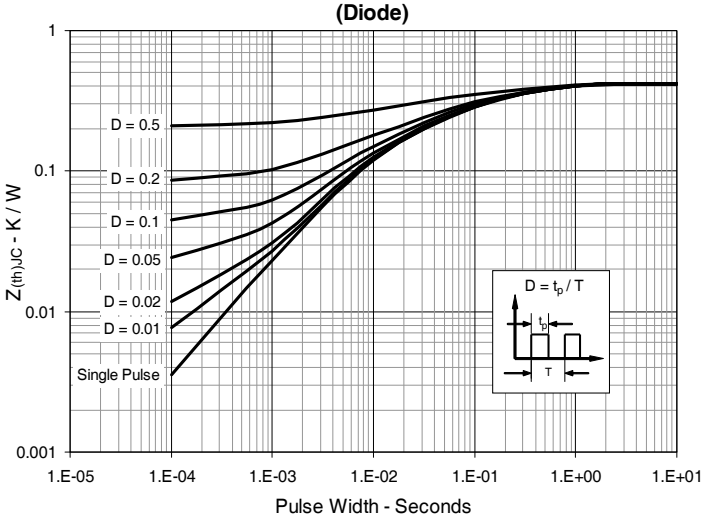


Fig. 26. Maximum Transient Thermal Impedance (Diode)



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